

Single Event Transient – I.

- 09:00-09:10 S-0 Welcome and Scope of Workshop **Reno Harboe Sørensen**
- 09:10-09:40 S-1 SET Generation & Definition – Overview **Andrew Chugg**
- 09:40-10:10 Radiation Induced SETs in Spacecrafts –
- S-2a SOHO **Reno Harboe Sørensen**
 - S-2b Telecom **Philippe Calvel/Ronan Marec**
 - S-2c CARMEN2/MEX **Francoise Bezerra**
- 10:10-10:40 Ground Test Facilities –
- S-3a Commonly Used **Wojtek Hajdas**
 - S-3b Laser/Sources **Andrew Chugg**
- 10:40-11:00 **Coffee Break**

Single Event Transient – II.

11:00-12:30 **Ground SET Testing –**

S-4a Overview –

S-4b Impact of Test Parameters

S-4c Experience by Test Laboratory

S-4d Examples and Lessons Learnt

Renaud Mangeret

Francoise Bezerra

Christian Chatry

Stanley Mattsson

12:30-14:00 **Lunch**

14:00-14:10 **S-5** **Propagation of SETs in Digital Circuits**

Veronique Ferlet-Cavrois

14:10-14:40 **S-6** **Implications on Design Level –
SET Mitigation/Modelling**

Sven Landstroem

Single Event Transient – III.

- 14:40-15:20 S-7 SET Rate Predictions –
Critical Issues/Realistic Assumptions **Renaud Mangeret**
- 15:20-15:40 **Coffee Break**
- 15:40-16:30 RHA Policy –
S-8a Agencies **Christian Poivey**
S-8b Industry **Michel Melotte**
- 16:30-16:50 S-9 Summary/Way Forward/Future Critical SET Issues
Reno Harboe Sørensen
- 17:00 End of Workshop on “Single Event Transient”.